

27C128

# **128K (16K x 8) CMOS EPROM**

# **FEATURES**

- · High speed performance
  - 120 ns access time available
- CMOS Technology for low power consumption
  - 20 mA Active current
  - 100 μA Standby current
- · Factory programming available
- · Auto-insertion-compatible plastic packages
- · Auto ID aids automated programming
- · Separate chip enable and output enable controls
- · High speed "express" programming algorithm
- Organized 16K x 8: JEDEC standard pinouts
  - 28-pin Dual-in-line package
  - 32-pin PLCC Package
  - 28-pin SOIC package
  - Tape and reel
- · Available for the following temperature ranges:

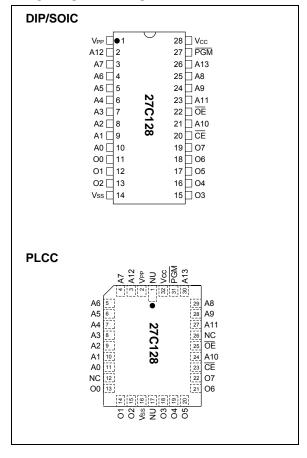
Commercial: 0°C to +70°C
 Industrial: -40°C to +85°C
 Automotive: -40°C to +125°C

# DESCRIPTION

The Microchip Technology Inc. 27C128 is a CMOS 128K bit (electrically) Programmable Read Only Memory. The device is organized as 16K words by 8 bits (16K bytes). Accessing individual bytes from an address transition or from power-up (chip enable pin going low) is accomplished in less than 120 ns. CMOS design and processing enables this part to be used in systems where reduced power consumption and high reliability are requirements. A complete family of packages is offered to provide the most flexibility in applications. For surface mount applications, PLCC, SOIC, or TSOP packaging is available. Tape and reel packaging is also available for PLCC or SOIC packages. UV erasable versions are also available.

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### **PACKAGE TYPES**



# 1.0 ELECTRICAL CHARACTERISTICS

# 1.1 Maximum Ratings\*

Vcc and input voltages w.r.t. Vss......-0.6V to +7.25V

VPP voltage w.r.t. Vss during
programming .....-0.6V to +14V

Voltage on A9 w.r.t. Vss....-0.6V to +13.5V

Output voltage w.r.t. Vss...-0.6V to Vcc +1.0V

Storage temperature ....-65°C to +150°C

Ambient temp. with power applied ....-65°C to +125°C

\*Notice: Stresses above those listed under "Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

TABLE 1-1: PIN FUNCTION TABLE

| Name    | Function                                    |
|---------|---|
| A0-A13  | Address Inputs                              |
| CE      | Chip Enable                                 |
| ŌĒ      | Output Enable                               |
| PGM     | Program Enable                              |
| VPP     | Programming Voltage                         |
| O0 - O7 | Data Output                                 |
| Vcc     | +5V Power Supply                            |
| Vss     | Ground                                      |
| NC      | No Connection; No Internal Connections      |
| NU      | Not Used; No External Connection Is Allowed |

TABLE 1-2: READ OPERATION DC CHARACTERISTICS

Vcc = +5V ( $\pm 10\%$ )Tamb =  $0^{\circ}$ C to  $+70^{\circ}$ CCommercial:Tamb =  $-40^{\circ}$ C to  $+85^{\circ}$ CExtended (Automotive):Tamb =  $-40^{\circ}$ C to  $+125^{\circ}$ C

Units **Parameter** Part\* Status Symbol Min. Max. **Conditions** Logic "1" Vcc+1 ٧ Input Voltages all VIH 2.0 Logic "0" VIL -0.5 8.0 V Input Leakage all ILI -10 10 μΑ VIN = 0 to VCC2.4  $IOH = -400 \mu A$ **Output Voltages** all Logic "1" Vон V Logic "0" Vol 0.45 ٧ IOL = 2.1 mAVout = 0V to Vcc Output Leakage all ILO -10 10 μΑ рF VIN = 0V: Tamb =  $25^{\circ}C$ : Input Capacitance all CIN 6 f = 1 MHzVout = 0V; Tamb =  $25^{\circ}C$ ; **Output Capacitance** all COUT 12 pF f = 1 MHzVCC = 5.5V; VPP = VCCPower Supply Current, С TTL input 20 ICC1 mΑ Active I,E TTL input ICC2 25 mΑ f = 1 MHz; $\overline{OE} = \overline{CE} = VIL;$ IOUT = 0 mA: VIL = -0.1 to 0.8V;VIH = 2.0 to VCC; Note 1 Power Supply Current, С TTL input Icc(s) 2 mΑ Standby I.E TTL input 3 mΑ all CMOS input 100 μΑ  $CE = Vcc \pm 0.2V$ **IPP Read Current** Read Mode **I**PP 100 VPP = 5.5Vall μΑ **VPP Read Voltage** all Read Mode **VPP** Vcc-0.7 Vcc

Note 1: Typical active current increases .75 mA per MHz up to operating frequency for all temperature ranges.

<sup>\*</sup> Parts: C=Commercial Temperature Range; I, E=Industrial and Extended Temperature Ranges

TABLE 1-3: READ OPERATION AC CHARACTERISTICS

AC Testing Waveform: VIH = 2.4V and VIL = 0.45V; VOH = 2.0V VOL = 0.8V

Output Load: 1 TTL Load + 100 pF

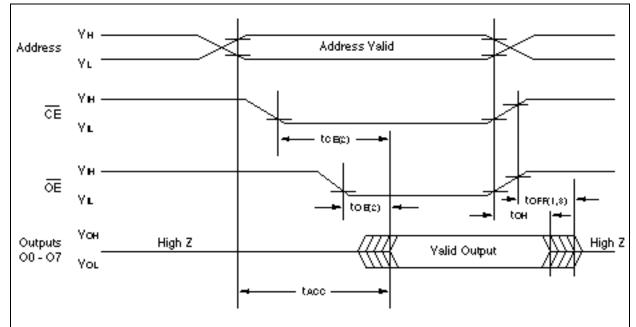
Input Rise and Fall Times: 10 ns

Ambient Temperature: Commercial: Tamb =  $0^{\circ}$ C to +70°C

Industrial: Tamb = -40°C to +85°C Extended (Automotive): Tamb = -40°C to +125°C

| Parameter   | Sym  | 27C128-12 |     | 27C128-15 |     | 27C128-17 |     | 27C128-20 |     | 27C128-25 |     | Units | Conditions         |  |
|---|------|-----------|-----|-----------|-----|-----------|-----|-----------|-----|-----------|-----|-------|--------------------|--|
| rarameter Sym   |      | Min       | Max | Units | Conditions         |  |
| Address to Output Delay   | tACC | _         | 120 | _         | 150 | _         | 170 | _         | 200 | _         | 250 | ns    | CE=OE=VIL          |  |
| CE to Output Delay  | tCE  | _         | 120 | _         | 150 | _         | 170 | _         | 200 | _         | 250 | ns    | <del>OE</del> =VIL |  |
| OE to Output Delay  | tOE  | _         | 65  | -         | 70  |           | 70  |           | 75  | l         | 100 | ns    | CE=VIL             |  |
| CE or OE to O/P High Impedance                                  | tOFF | 0         | 50  | 0         | 50  | 0         | 50  | 0         | 55  | 0         | 60  | ns    |                    |  |
| Output Hold from<br>Address CE or OE,<br>whichever occurs first | ton  | 0         | 1   | 0         | 1   | 0         | 1   | 0         | _   | 0         | _   | ns    |                    |  |

### FIGURE 1-1: READ WAVEFORMS



Notes: (1) topp is specified for  $\overline{OE}$  or  $\overline{CE}$ , whichever occurs first

- (2) OE may be delayed up to to E-to Eafter the falling edge of CE without impact on to E
- (3) This parameter is sampled and is not 100% tested.

TABLE 1-4: PROGRAMMING DC CHARACTERISTICS

|                               | Ambient Temperature: Tamb = $25^{\circ}$ C $\pm 5^{\circ}$ C VCC = $6.5$ V $\pm 0.25$ V, VPP = $13.0$ V $\pm 0.25$ V |   |             |              |        |                               |  |  |  |  |  |
|-------------------------------|--|---|-------------|--------------|--------|-------------------------------|--|--|--|--|--|
| Parameter                     | Status   | Status Symbol Min Max. Units Conditions |             |              |        |                               |  |  |  |  |  |
| Input Voltages                | Logic"1"<br>Logic"0"   | VIH<br>VIL                              | 2.0<br>-0.1 | Vcc+1<br>0.8 | V<br>V |                               |  |  |  |  |  |
| Input Leakage                 | _  | ILI                                     | -10         | 10           | μΑ     | VIN = 0V to VCC               |  |  |  |  |  |
| Output Voltages               | Logic"1"<br>Logic"0"   | Voh<br>Vol                              | 2.4         | 0.45         | V<br>V | IOH = -400 μA<br>IOL = 2.1 mA |  |  |  |  |  |
| Vcc Current, program & verify | _  | ICC2                                    | _           | 20           | mA     | Note 1                        |  |  |  |  |  |
| VPP Current, program          | _  | IPP2                                    | _           | 25           | mA     | Note 1                        |  |  |  |  |  |
| A9 Product Identification     | _  | VH                                      | 11.5        | 12.5         | V      |                               |  |  |  |  |  |

Note 1: VCC must be applied simultaneously or before VPP and removed simultaneously or after VPP

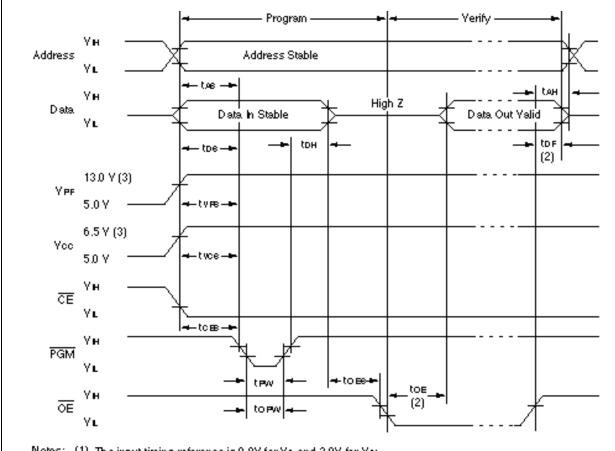
# TABLE 1-5: PROGRAMMING AC CHARACTERISTICS

| for Program, Program Verify and Program Inhibit Modes AC Testing Waveform: VIH=2.4V and VIL=0.45V; VOH=2.0V; VOL=0.8V Ambient Temperature: Tamb= $25^{\circ}$ C± $5^{\circ}$ C VCC= $6.5$ V ± $0.25$ V, VPP = VH = $13.0$ V ± $0.25$ V |        |     |     |       |                |  |  |  |  |
|--|--------|-----|-----|-------|----------------|--|--|--|--|
| Parameter  | Symbol | Min | Max | Units | Remarks        |  |  |  |  |
| Address Set-Up Time  | tAS    | 2   | _   | μs    |                |  |  |  |  |
| Data Set-Up Time   | tDS    | 2   | _   | μs    |                |  |  |  |  |
| Data Hold Time   | tDH    | 2   | _   | μs    |                |  |  |  |  |
| Address Hold Time  | tah    | 0   | _   | μs    |                |  |  |  |  |
| Float Delay (2)  | tDF    | 0   | 130 | ns    |                |  |  |  |  |
| Vcc Set-Up Time  | tvcs   | 2   | _   | μs    |                |  |  |  |  |
| Program Pulse Width (1)  | tpw    | 95  | 105 | μs    | 100 μs typical |  |  |  |  |
| CE Set-Up Time   | tces   | 2   | _   | μs    |                |  |  |  |  |
| OE Set-Up Time   | toes   | 2   | _   | μs    |                |  |  |  |  |
| VPP Set-Up Time  | tvps   | 2   | _   | μs    |                |  |  |  |  |
| Data Valid from OE   | tOE    |     | 100 | ns    |                |  |  |  |  |

Note 1: For express algorithm, initial programming width tolerance is 100  $\mu$ s  $\pm 5\%$ .

<sup>2:</sup> This parameter is only sampled and not 100% tested. Output float is defined as the point where data is no longer driven (see timing diagram).

FIGURE 1-2: **PROGRAMMING WAVEFORMS (1)** 



Notes: (1) The input timing reference is 0.8Y for YL and 2.0Y for YH.

- (2) to pand to pare characteristics of the device but must be accommodated by the programmer.
- (3)  $Voc = 6.5Y \pm 0.25Y$ ,  $Vpp = VH = 13.0Y \pm 0.25Y$  for Express algorithm.

**TABLE 1-6: MODES** 

| Operation Mode  | CE  | ŌĒ  | PGM | <b>V</b> PP | A9 | O0 - O7       |
|-----------------|-----|-----|-----|-------------|----|---------------|
| Read            | VIL | VIL | VIH | Vcc         | Х  | Dout          |
| Program         | VIL | VIH | VIL | VH          | Х  | DIN           |
| Program Verify  | VIL | VIL | VIH | VH          | X  | Douт          |
| Program Inhibit | VIH | Х   | X   | VH          | Χ  | High Z        |
| Standby         | VIH | Х   | Х   | Vcc         | Χ  | High Z        |
| Output Disable  | VIL | VIH | VIH | Vcc         | Χ  | High Z        |
| Identity        | VIL | VIL | VIH | Vcc         | VH | Identity Code |

X = Don't Care

#### 1.2 Read Mode

(See Timing Diagrams and AC Characteristics) Read Mode is accessed when

- the CE pin is low to power up (enable) the chip
- b) the  $\overline{OE}$  pin is low to gate the data to the output pins

For Read operations, if the addresses are stable, the address access time (tACC) is equal to the delay from CE to output (tCE). Data is transferred to the output after a delay from the falling edge of  $\overline{OE}$  (toe).

# 1.3 Standby Mode

The standby mode is defined when the  $\overline{CE}$  pin is high (VIH) and a program mode is not defined.

When these conditions are met, the supply current will drop from 20 mA to 100  $\mu$ A.

### 1.4 Output Enable

This feature eliminates bus contention in microprocessor-based systems in which multiple devices may drive the bus. The outputs go into a high impedance state when the following condition is true:

• The OE and PGM pins are both high.

# 1.5 <u>Erase Mode (U.V. Windowed Versions)</u>

Windowed products offer the capability to erase the memory array. The memory matrix is erased to the all 1's state when exposed to ultraviolet light. To ensure complete erasure, a dose of 15 watt-second/cm² is required. This means that the device window must be placed within one inch and directly underneath an ultraviolet lamp with a wavelength of 2537 Angstroms, intensity of  $12,000\mu\text{W/cm}^2$  for approximately 20 minutes.

# 1.6 **Programming Mode**

The Express Algorithm has been developed to improve the programming throughput times in a production environment. Up to ten 100-microsecond pulses are applied until the byte is verified. No overprogramming is required. A flowchart of the express algorithm is shown in Figure 1-3.

Programming takes place when:

- a) Vcc is brought to the proper voltage,
- b) VPP is brought to the proper VH level,
- c) the CE pin is low,
- d) the  $\overline{OE}$  pin is high, and
- e) the  $\overline{PGM}$  pin is low.

Since the erased state is "1" in the array, programming of "0" is required. The address to be programmed is set via pins A0-A13 and the data to be programmed is presented to pins O0-O7. When data and address are stable,  $\overline{OE}$  is high,  $\overline{CE}$  is low and a low-going pulse on the  $\overline{PGM}$  line programs that location.

# 1.7 Verify

After the array has been programmed it must be verified to ensure all the bits have been correctly programmed. This mode is entered when all the following conditions are met:

- a) Vcc is at the proper level,
- b) VPP is at the proper VH level,
- c) the CE line is low,
- d) the PGM line is high, and
- e) the OE line is low.

### 1.8 Inhibit

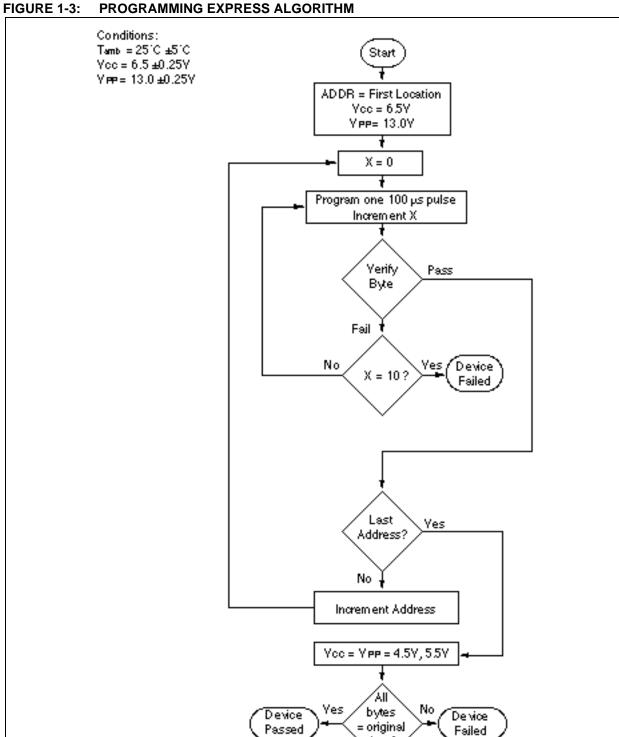
When programming multiple devices in parallel with different data, only  $\overline{CE}$  or  $\overline{PGM}$  need be under separate control to each device. By pulsing the  $\overline{CE}$  or  $\overline{PGM}$  line low on a particular device in conjunction with the  $\overline{PGM}$  or  $\overline{CE}$  line low, that device will be programmed; all other devices with  $\overline{CE}$  or  $\overline{PGM}$  held high will not be programmed with the data, although address and data will be available on their input pins (i.e., when a high level is present on  $\overline{CE}$  or  $\overline{PGM}$ ); and the device is inhibited from programming.

### 1.9 <u>Identity Mode</u>

In this mode specific data is output which identifies the manufacturer as Microchip Technology Inc. and device type. This mode is entered when Pin A9 is taken to VH (11.5V to 12.5V). The  $\overline{\text{CE}}$  and  $\overline{\text{OE}}$  lines must be at VIL. A0 is used to access any of the two non-erasable bytes whose data appears on O0 through O7.

| Pin —                        | Input      | Output |        |        |        |        |        |   |     |             |
|------------------------------|------------|--------|--------|--------|--------|--------|--------|---|-----|-------------|
| Identity                     | Α0         | 0<br>7 | O<br>6 | O<br>5 | O<br>4 | O<br>3 | O<br>2 | 0 | 0 0 | H<br>e<br>x |
| Manufacturer<br>Device Type* | VIL<br>VIH | 0<br>1 | 0<br>0 | 1<br>0 | 0      | 1<br>0 | 0      | 0 | 1   | 29<br>83    |

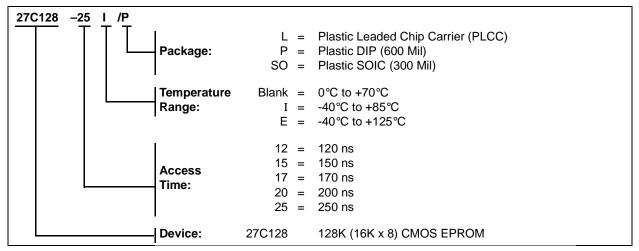
<sup>\*</sup> Code subject to change



data?

# 27C128 Product Identification System

To order or to obtain information, e.g., on pricing or delivery, please use the listed part numbers, and refer to the factory or the listed sales offices.



#### Note the following details of the code protection feature on Microchip devices:

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CERTIFIED BY DNV

ISO/TS 16949:2002 ===

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